



PTO/SB/08A (10-01)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO.

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet

1

of

2

Complete if Known

Application Number	10/663,587
Filing Date	September 16, 2003
First Named Inventor	Guy T. Blalock
Group Art Unit	Unknown 2829
Examiner Name	Unknown TANG
Attorney Docket Number	2269-4716US (00-0991.00/US)

U.S. PATENT DOCUMENTS

Examiner Initials *	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
MT		US-5,065,201	11/12/1991	Yamauchi	---
		US- 5,315,145	05/24/1994	Lukaszek	---
		US- 5,594,328	01/14/1997	Lukaszek	---
		US- 8,051,443	04/18/2000	Ghio et al.	---
		US- 6,140,833	10/31/2000	Flietner et al.	---
MT		US- 6,144,037	11/07/2000	Ryan et al.	---
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			
		US-			

CLASS
SUB
CLASS**FOREIGN PATENT DOCUMENTS**

Examiner Initials *	Cite No. ¹	Foreign Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁴
		Country Code ³ - Number ⁴ - Kind Code ⁵ (if known)				

Examiner
Signature

Minh Tang

Date
Considered

4/11/05

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.



PTO/SB/08B(10-01)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number

Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(use as many sheets as necessary)

Sheet 2

of

2

Complete if Known

Application Number	10/663,587
Filing Date	September 16, 2003
First Named Inventor	Guy T. Blalock
Group Art Unit	Unknown 2829
Examiner Name	Unknown TANG
Attorney Docket Number	2269-47161US (00-0991 00/1 IS)

OTHER PRIOR ART -- NON PATENT LITERATURE DOCUMENTS

Examiner Initials *	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²
MT		BOEDO, J., "UCSD-FERP Boundary Diagnostics for NSTX," NSTX PAC Meeting, May 1997, 6 pages.	
		"Fast Reciprocating Probes for Edge Profile Characterization on NSTX," January 1998, 1 page.	
		LUKASZEK et al., "CHARM: A New Wafer Surface Charge Monitor, TechCon '90, San Jose, 4 pages. (no month/year)	
		MOYER, Rick, "Langmuir Probes and Boundary Plasma Measurements," DIII-D News, http://fusion.gat.com/DNT/DNT21.htm , August 1994, 3 pages.	
		MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-11.	
		MOYER, Rick, "UC San Diego Boundary Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-12.	
		MOYER, Rick, "UC San Diego Fluctuation and Turbulent Transport Diagnostics for NSTX," NSTX FY98 Research Forum, December 1997, pp. 1-8.	
MT		RUDAKOV, D.L. et al., "Probe Diagnostics," http://www.rsfyssc.anu.edu.au/prl/probht.html , date unknown, 4 pages.	

Examiner
SignatureDate
Considered

4/11/05

* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number (optional). ² Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.